## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination OHMI ET AL. | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2005/0118829	06-2005	Lee et al.	438/714
*	В	US-2004/0063331	04-2004	Mori et al.	438/714
*	С	US-6,803,318	10-2004	Qiao et al.	438/700
*	D	US-6,406,640	06-2002	Yang et al.	216/67
*	Е	US-6,746,961	06-2004	Ni et al.	438/700
*	F	US-6,780,342	08-2004	Hagihara et al.	216/67
*	G	US-6,828,251	12-2004	Su et al.	438/724
*	Н	US-6,337,277	01-2002	Chou et al.	438/689
*	ı	US-2005/0263487	12-2005	Tsuchiya, Kazuo	216/067
*	J	US-6,083,845	07-2000	Yang et al.	438/734
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Ø					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	C						
	V						
	w						
	х						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.